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L6	217	5 and "708"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 16:41
L7	80	(shift.ti. or shift.clm. or shift.ab.) and 6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:02
L8	22	"4866652"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:02
L9	17	("4866652").URPN.	USPAT	OR	ON	2005/02/01 17:02
L10	1	("4760551").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/02/01 17:02
L11	326	708/495,501,708.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/01 17:50

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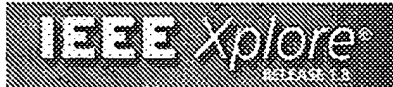
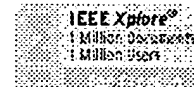
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*Demoment, G.; Reynaud, R.;*

Instrumentation and Measurement Technology Conference, 1993. IMTC/93.

Conference Record., IEEE , 18-20 May 1993

Pages:391 - 396

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#### 2 A VLIW architecture for logarithmic arithmetic

*Arnold, M.G.;*

Digital System Design, 2003. Proceedings. Euromicro Symposium on , 1-6

Sept. 2003

Pages:294 - 302

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